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**Chemical C-V Measurements on ZnO** SARAH JANE GABIG, GARY FARLOW, Wright State University — When metal/semiconductor schotky barriers are not practical, an electrolyte/semiconductor interface can be used to make capacitance-voltage (C-V) measurements. The physics of such electrochemical C-V measurements will be described. Electrical properties of ZnO were measured by electrochemical C-V techniques and photovoltage spectroscopy using an Accent 4400 Electrochemical CV system. Specifically, the electrical behavior of a 0.1 M ZnCl<sub>2</sub> electrolyte-ZnO interface has been investigated with attention to the electrolyte-ZnO interface's C-V dependence on carrier frequency.

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